

AMENDMENTS TO THE CLAIMS

This listing of the claims will replace all previous versions thereof.

1. (Currently Amended) A method of inspecting a workpiece, comprising generating an array of charged particle beams; passing each of the charged particle beams through one of a plurality of pole pieces, there being one pole piece associated with each charged particle beam, and through a single lens coil surrounding the plurality of pole pieces; directing the array of charged particle beams onto a area of the workpiece so as to produce secondary or backscattered particles; detecting the secondary or backscattered particles; ~~and~~ reconstructing an image of the area of the workpiece from detected ones of the secondary or backscattered particles; determining if one of the charged particle beams has failed; and translating the workpiece relative to the array of charged particle beams, thereby to direct a remaining one of the charged particle beams onto that portion of the workpiece onto which the failed beam was intended to be incident.
2. (Original) The method of claim 1, wherein each of the charged particle beams is directed onto a different region of the workpiece.
3. (Currently Amended) The method of claim 1, ~~further comprising translating wherein~~ the workpiece is translated relative to an axis of the array of charged particle beams.
4. (Cancelled)

5. (Previously Presented) The method of claim 1, further comprising focusing individually each of the charged particle beams onto the workpiece; and providing a plurality of additional focusing fields, one associated with each of the beams.

6. (Previously Presented) The method of claim 5, wherein the additional focusing fields are located at a perimeter of the array of charged particle beams.